

Notice of References Cited	Application/Control No. 10/561,396	Applicant(s)/Patent Under Reexamination YAYON, AVNER	
	Examiner Ron Schwadron, Ph.D.	Art Unit 1644	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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FOREIGN PATENT DOCUMENTS

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	N	WO 00/27379	05-2000	WO	Yayon et al.	---
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NON-PATENT DOCUMENTS

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